

*Physics*

## Physico-Mechanical Properties of $\text{Si}_{0.85}\text{Ge}_{0.15}:\text{GaP}$ Alloy

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**ABSTRACT.** Internal friction and shear modulus temperature and amplitude dependences of  $\text{Si}_{0.85}\text{Ge}_{0.15}:\text{GaP}$  alloy were investigated. Relaxation processes of dislocation origin were revealed and their activation characteristics determined. The mechanism of internal friction relaxation processes was analyzed from the point of view of geometrical and double-kink migration on the screw and  $60^\circ$  dislocations. © 2007 Bull. Georg. Natl. Acad. Sci.

**Key words:** doped silicon, internal friction, shear modulus, relaxation, activation energy, dislocation.

Silicon-germanium alloys form a fully miscible solid solution with diamond crystal structure. These alloys have caused considerable interest due to their potential for band-gap and lattice-parameter engineering. Bulk SiGe alloys can be used as X-ray neutron monochromators and solar cells. They can also provide a lattice-matched substrate for SiGe epitaxial growth instead of Si.

It is known that doping of Si-Ge alloys by GaP [1] changes their thermoelectrical properties so that carrier concentration mobility in relation to thermal conductivity increases. According to this, it is possible to regulate the thermoelectrical properties of Si-Ge alloys in a wide range. Si-Ge solid solutions have been doped by GaP to obtain *n*-type crystals. The crystals are characterized by relatively low thermal conductivity and high Seebeck coefficient. It is remarkable that GaP-doped Si-Ge alloys are characterized by high-temperature diffusion activity of constituent components and high concentration and mobility of defects [2]. This determines various electro-physical parameters of the mentioned alloys. Therefore, it is necessary to carry out an investigation of the structural sensitivity of the physical properties in the initial state and after thermal treatment.

In this work we have studied the internal friction and relative shear modulus of GaP-doped Si-Ge alloy in the area of frequency of torsion oscillations of  $\sim 1\text{Hz}$  and at temperature range of  $20\text{-}800^\circ\text{C}$ . The measurements were carried out at the amplitude of oscillatory deformation  $5 \cdot 10^{-5}$ , at which internal friction intensity dependence on the amplitude of oscillation is not expected. The temperature spectrum of internal friction is rich in maxima. They are revealed at the temperatures of  $100, 375, 390, 470, 560$  and  $670^\circ\text{C}$  (Fig.1). The first maximum is characteristic of a silicon single crystal with perfect structure [3]. The relaxation internal friction of similar origin is revealed in Si-Ge system alloys with small concentration of germanium ( $0 \leq \text{Ge} \leq 0.01$ ) [4]. The internal friction background at room temperature is characterized by a strong dependence on amplitude. This fact confirms its dislocation origin. The temperatures of revealed maxima in the spectrum of internal friction depend on oscillation frequency. So, they are of relaxation nature. The values of activation energy are determined by the method of frequency shift of relaxation internal friction maxima:  $0.80; 1.40; 1.50; 1.65; 1.85; \text{and } 2.00\text{eV}$ . Their frequency factors are respectively:  $5 \cdot 10^{11}, 5 \cdot 10^{13}, 2 \cdot 10^{12}, 1 \cdot 10^{12}$  and  $3 \cdot 10^{11}\text{sec}^{-1}$ .

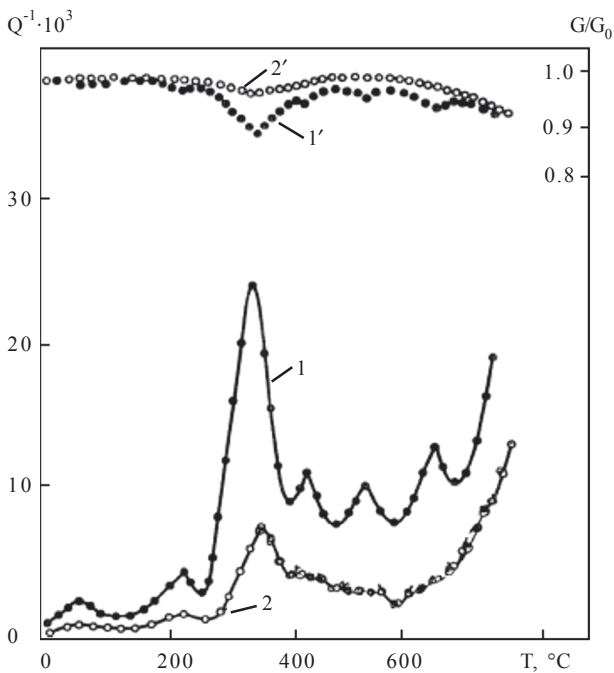


Fig. 1. Temperature spectra of internal friction ( $Q^{-1}$ ) and relative shear modulus ( $G/G_0$ ) of  $Si_{0.85}Ge_{0.15}:GaP$  alloy: 1.1' - ( $Q^{-1}$ ) and ( $G/G_0$ ), initial state; 2.2' - ( $Q^{-1}$ ) and ( $G/G_0$ ), after annealing at  $850^\circ C$ , 50 hrs.

At the comparative high frequency ( $\sim 5\text{Hz}$ ) of oscillation in the temperature range of  $300\text{--}700^\circ C$  the internal friction background intensity decreases by  $\sim 15\%$ . In the case of repeated measurements the critical values of oscillation amplitude increase, at which a significant increase of internal friction intensity begins.

During torsion oscillations, the deformation at room temperature practically has no effect on the shape and intensity of the internal friction spectrum obtained by

repeated measurements. High temperature ( $\sim 700^\circ C$ ) cyclic deformation at the amplitude  $\sim 10^{-3}$  significantly increases the intensity of internal friction ( $\sim 20\%$ ) and gives rise to broadening of the above-mentioned relaxation origin maxima. This variation is caused by microplastic deformation under a high amplitude of oscillation at the temperature  $700^\circ C$ . At high amplitude of oscillatory deformation generation of fresh dislocation is possible. Also, at high-amplitude oscillatory deformation the existing pinned dislocation segments may be detached from the pinning centers.

Annealing of alloys at  $850^\circ C$  for 50 hrs will cause the elimination of some relaxation centers, strong pinning of dislocations by point defects and their complexes. After long-term annealing, the intensity of internal friction maxima is significantly decreased. At temperature  $\sim 380^\circ C$  there exists a low intensity maximum, but simultaneously the high-temperature internal friction background exponentially increases. After annealing a wide maximum is revealed at the temperature  $380^\circ C$ , which is characterized by the activation energy  $\sim 1.60\text{eV}$ , its frequency factor equalling  $\sim 5 \cdot 10^{12}\text{sec}^{-1}$ .

In the initial state a temperature spectrum of shear modulus with complex form was observed. Shear modulus decreases at temperatures of internal friction maxima. The local character of shear modulus decrease is due to a relaxation process taking place under the effect of temperature and periodical stress. Above  $500^\circ C$  steps and saturated areas exist on the shear modulus curve. Such changes of shear modulus are possible due to the high diffusion activities of oxygen, carbon and phosphorus atoms at high temperatures.

Table 1

The physico-mechanical characteristics of the GaP-doped Si-Ge alloy at fixed temperature

Si-Ge system alloy	Temperature, $^\circ C$	Shear modulus, $\times 10^3, \text{kG/mm}^2$	I critical amplitude $\times 10^4$	II critical amplitude $\times 10^4$	Elasticity limit, $\text{kG/mm}^2$	
					I	II
$Si_{0.85}Ge_{0.15}$ doped with GaP	20	3.6	0.8	30	30.8	108
	150	3.45	0.6	25	21.7	86
	250	3.40	0.45	20	15.8	72
	350	3.30	0.4	13.0	13.2	43
	450	3.20	0.30	11.0	9.6	35
	550	3.15	0.20	10.0	6.3	31.5
	650	3.0	0.15	8.0	4.5	24

After annealing at  $750^\circ\text{C}$  for 50hrs there occurs dynamic strengthening of the  $\text{Si}_{0.85}\text{Ge}_{0.15}\text{:GaP}$  alloy. It is known [5] that in the process of high temperature annealing, migration of impurity atoms in the direction of dislocation cores accelerates. As a result, atmospheres of impurity atoms originate around the dislocations. In consequence of the above-mentioned dislocation blocking takes place. Owing to this, an increase of dynamical shear modulus is observed. Some physico-mechanical characteristics of the investigated sample are presented in Table 1.

Dislocation density increase of GaP doped Si-Ge alloy is achieved by deformation at high temperatures. This fact and the local, inhomogeneously distributed strains, generated by doping atoms have a strong effect on the distribution of technology impurities, and doping atoms and on the activation characteristics of the motion of dislocations. At  $700^\circ\text{C}$  high-amplitude deformation ( $\sim 5 \cdot 10^{-3}$ ), in conditions of 1.5Hz frequency and 200 cycles of torsional oscillations of the  $\text{Si}_{0.85}\text{Ge}_{0.15}\text{:GaP}$  alloy in the amplitude range of  $1 \cdot 10^{-5}$ – $8 \cdot 10^{-5}$ , reveals a slow decrease of shear modulus and sharp increase of internal friction intensity. After achievement of  $7 \cdot 10^{-4}$  amplitude of oscillatory deformation, the following measurements in the range of  $5 \cdot 10^{-4}$ – $5 \cdot 10^{-5}$  oscillatory deformation at amplitude decrease have revealed internal friction hysteretic change (Fig. 2).

The results of internal friction amplitude dependence measurements at high temperatures ( $400$ – $600^\circ\text{C}$ ) are practically identical with the results obtained at room temperature. The difference is that the internal friction hysteresis increases with an increase of temperature, the critical amplitude of oscillatory deformation decreases at high temperatures, at which a sharp increase of the scattering energy of oscillations begins. Annealing at  $500^\circ\text{C}$  for 2hrs causes dislocation pinning. Accordingly, the internal friction hysteresis decreases, completely disappearing in the low range of amplitude ( $1 \cdot 10^{-5}$ – $5 \cdot 10^{-5}$ ). The amplitude dependence internal friction of the  $\text{Si}_{0.85}\text{Ge}_{0.15}$  alloy deformed by compression is of more complicated nature.

The shear modulus reveals complex dependence on the amplitude of oscillation in the deformed  $\text{Si}_{0.85}\text{Ge}_{0.15}\text{:GaP}$  alloy. We have studied the amplitude dependence of the torsion oscillations frequency square for cyclic deformed crystals at  $700^\circ\text{C}$  and for crystals that are deformed by one-axis pressure. Both types of deformation cause hysteretic change of shear modulus, at the increase and decrease of amplitude cycles. Decreased values of the shear modulus are recorded on the

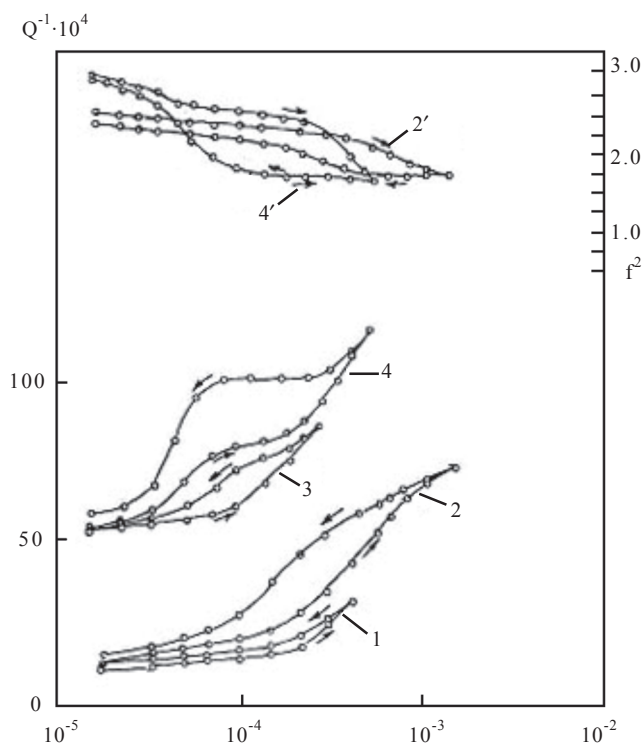


Fig. 2. Amplitude dependence of internal friction (1,2,3,4) and shear modulus in  
1, 2, 2' – cyclic deformation,  $700^\circ\text{C}$   
3, 4, 4' – one-axis pressure deformation,  $700^\circ\text{C}$ .

return amplitude dependence curve. It is supposed that as a result of deformation, the bulk of doping impurities exist in solid solution, which causes local tensile deformation in the crystal lattice of  $\text{Si}_{0.85}\text{Ge}_{0.15}\text{:GaP}$  alloy.

Simultaneously originated dislocations by deformation exist in completely free or weak binding areas. Both of the above-mentioned factors cause a decrease of shear modulus, which is clearly revealed on the shear modulus curve. The internal friction maximum, observed at temperatures from  $300$  to  $800^\circ\text{C}$ , are of dislocation character. They are analogous to the maxima observed in torsionally deformed fiber-type silicon single crystals [6]. They may be analyzed by the Zeeger model of nucleation of dislocation kinks [7].

Considering the peculiarities of the dislocation internal friction, we may assume that the maxima, observed in the internal friction spectrum at  $390$  and  $470^\circ\text{C}$ , are provided by migration of geometric kinks on  $60^\circ$  and screw dislocations, respectively, while the maxima observed at  $560$  and  $670^\circ\text{C}$ , may be attributed to the processes of nucleation and migration of double kinks on screw and  $60^\circ$ -dislocations in the  $\text{Si}_{0.85}\text{Ge}_{0.15}\text{:GaP}$  alloy.

ფიზიკა

## $\text{Si}_{0,85}\text{Ge}_{0,15}:\text{GaP}$ შენადნობის ფიზიკურ-მექანიკური თვისებები

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შესწავლილია გალიუმის ფოსფიდით ლეგირებული  $\text{Si}_{0,85}\text{Ge}_{0,15}$  შენადნობის შინაგანი ხახუნისა და ძვრის მოდულის ტემპერატურული და ამპლიტუდური დამოკიდებულებები. გამოვლენილია დისლოკაციური წარმოშობის რელაქსაციური პროცესები. განსაზღვრულია მათი აქტივაციური მახასიათებლები. რელაქსაციური შინაგანი ხახუნის პროცესების მექანიზმები გაანალიზებულია ხრანულ და  $60^\circ$ -დისლოკაციებზე გეომეტრიული და წვეილი ღუნვების მოძრაობის ასპექტში.

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